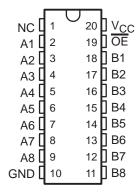
- High-Bandwidth Data Path (Up to 500 MHz[†])
- Equivalent to IDTQS3VH384 Device
- 5-V Tolerant I/Os with Device Powered-Up or Powered-Down
- Low and Flat ON-State Resistance (r_{on})
 Characteristics Over Operating Range (r_{on} = 4 Ω Typical)
- Rail-to-Rail Switching on Data I/O Ports
 0- to 5-V Switching With 3.3-V V_{CC}
 - 0- to 3.3-V Switching With 2.5-V V_{CC}
- Bidirectional Data Flow, With Near-Zero Propagation Delay
- Low Input/Output Capacitance Minimizes Loading and Signal Distortion (C_{io(OFF)} = 3.5 pF Typical)
- Fast Switching Frequency (foe = 20 MHz Max)
 - † For additional information regarding the performance characteristics of the CB3Q family, refer to the TI application report, CBT-C, CB3T, and CB3Q Signal-Switch Families, literature number SCDA008.

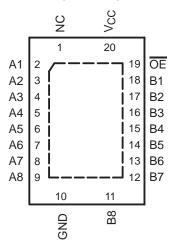
DBQ, DGV, OR PW PACKAGE (TOP VIEW)



NC - No internal connection

- Data and Control Inputs Provide Undershoot Clamp Diodes
- Low Power Consumption (I_{CC} = 1 mA Typical)
- V_{CC} Operating Range From 2.3 V to 3.6 V
- Data I/Os Support 0 to 5-V Signaling Levels (0.8-V, 1.2-V, 1.5-V, 1.8-V, 2.5-V, 3.3-V, 5-V)
- Control Inputs Can be Driven by TTL or 5-V/3.3-V CMOS Outputs
- I_{off} Supports Partial-Power-Down Mode Operation
- Latch-Up Performance Exceeds 100 mA Per JESD 78, Class II
- ESD Performance Tested Per JESD 22
 - 2000-V Human-Body Model (A114-B, Class II)
 - 1000-V Charged-Device Model (C101)
- Supports Both Digital and Analog Applications: PCI Interface, Differential Signal Interface, Memory Interleaving, Bus Isolation, Low-Distortion Signal Gating

RGY PACKAGE (TOP VIEW)



NC - No internal connection



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description/ordering information

The SN74CB3Q3245 is a high-bandwidth FET bus switch utilizing a charge pump to elevate the gate voltage of the pass transistor, providing a low and flat ON-state resistance (ron). The low and flat ON-state resistance allows for minimal propagation delay and supports rail-to-rail switching on the data input/output (I/O) ports. The device also features low data I/O capacitance to minimize capacitive loading and signal distortion on the data bus. Specifically designed to support high-bandwidth applications, the SN74CB3Q3245 provides an optimized interface solution ideally suited for broadband communications, networking, and data-intensive computing systems.

The SN74CB3Q3245 is organized as an 8-bit bus switch with a single output-enable (\overline{OE}) input. When \overline{OE} is low, the bus switch is ON and the A port is connected to the B port, allowing bidirectional data flow between ports. When \overline{OE} is high, the bus switch is OFF and a high-impedance state exists between the A and B ports.

This device is fully specified for partial-power-down applications using I_{off} . The I_{off} circuitry prevents damaging current backflow through the device when it is powered down. The device has isolation during power off.

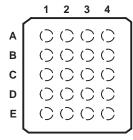
To ensure the high-impedance state during power up or power down, OE should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

ORDERING INFORMATION

TA	PACKAGE	<u>:</u> †	ORDERABLE PART NUMBER	TOP-SIDE MARKING	
	QFN – RGY	Tape and reel	SN74CB3Q3245RGYR	BU245	
	SSOP (QSOP) – DBQ Tape and reel		SN74CB3Q3245DBQR	CB3Q3245	
4000 1- 0500		Tube	SN74CB3Q3245PW	DUIGAE	
-40°C to 85°C	TSSOP – PW	Tape and reel	SN74CB3Q3245PWR	BU245	
	TVSOP - DGV	Tape and reel	SN74CB3Q3245DGVR	BU245	
	VFBGA – GQN	Tape and reel	SN74CB3Q3245GQNR	BU245	

[†]Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.

GQN PACKAGE (TOP VIEW)



terminal assignments

	1	2	3	4
Α	A1	NC	VCC	OE
В	А3	B2	A2	B1
С	A5	A4	B4	В3
D	A7	B6	A6	B5
Е	GND	A8	B8	B7

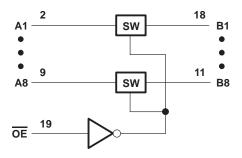
NC - No internal connection

FUNCTION TABLE

INPUT OE	INPUT/OUTPUT A	FUNCTION
L	В	A port = B port
Н	Z	Disconnect

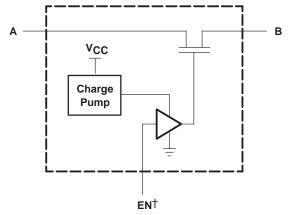


logic diagram (positive logic)



Pin numbers shown are for the DBQ, DGV, PW, and RGY packages.

simplified schematic, each FET switch (SW)



[†]EN is the internal enable signal applied to the switch.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage range, V _{CC}	-0.5 V to 4.6 V
Control input voltage range, V _{IN} (see Notes 1 and 2)	0.5 V to 7 V
Switch I/O voltage range, V _{I/O} (see Notes 1, 2, and 3)	0.5 V to 7 V
Control input clamp current, I _{IK} (V _{IN} < 0)	
I/O port clamp current, $I_{I/OK}$ ($V_{I/O}$ < 0)	
ON-state switch current, I _{I/O} (see Note 4)	±64 mA
Continuous current through V _{CC} or GND terminals	±100 mA
Package thermal impedance, θ _{JA} (see Note 5): DBQ package	68°C/W
(see Note 5): DGV package	92°C/W
(see Note 5): GQN package	78°C/W
(see Note 5): PW package	83°C/W
(see Note 6): RGY package	37°C/W
Storage temperature range, T _{stg}	. −65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. All voltages are with respect to ground unless otherwise specified.

- 2. The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
- 3. V_I and V_O are used to denote specific conditions for V_{I/O}.
- 4. II and IO are used to denote specific conditions for II/O.
- 5. The package thermal impedance is calculated in accordance with JESD 51-7.
- 6. The package thermal impedance is calculated in accordance with JESD 51-5.

recommended operating conditions (see Note 7)

		MIN	MAX	UNIT
Vcc	Supply voltage	2.3	3.6	V
	$V_{CC} = 2.3 \text{ V to } 2.7$	1.7	5.5	
VIH	High-level control input voltage $V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2	5.5	V
	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	0	0.7	
VIL	Low-level control input voltage $V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	0	0.8	V
V _{I/O}	Data input/output voltage	0	5.5	V
TA	Operating free-air temperature	-40	85	°C

NOTE 7: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.



electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER TEST CONDITIONS		IS	MIN	TYP†	MAX	UNIT		
VIK		V _{CC} = 3.6 V,	$I_{I} = -18 \text{ mA}$				-1.8	V
I _{IN}	Control inputs	V _{CC} = 3.6 V,	$V_{IN} = 0 \text{ to } 5.5 \text{ V}$				±1	μΑ
I _{OZ} ‡		V _{CC} = 3.6 V,	$V_O = 0$ to 5.5 V, $V_I = 0$,	Switch OFF, V _{IN} = V _{CC} or GND			±1	μΑ
l _{off}		$V_{CC} = 0$,	$V_0 = 0 \text{ to } 5.5 \text{ V},$	V _I = 0			1	μΑ
ICC		V _{CC} = 3.6 V,	I _{I/O} = 0, Switch ON or OFF,	$V_{IN} = V_{CC}$ or GND		1	2	mA
∆l _{CC} §	Control inputs	V _{CC} = 3.6 V,	One input at 3 V, Other inputs at V _{CC} or GND				30	μΑ
^I CCD [¶]	Per control input	V _{CC} = 3.6 V, Control input switching	A and B ports open, at 50% duty cycle			0.30	0.35	mA/ MHz
C _{in}	Control inputs	$V_{CC} = 3.3 \text{ V},$	V _{IN} = 5.5 V, 3.3 V, or 0			2.5	3.5	pF
C _{io(OFF}	=)	V _{CC} = 3.3 V,	Switch OFF, V _{IN} = V _{CC} or GND,	V _{I/O} = 5.5 V, 3.3 V, or 0		3.5	5	pF
C _{io(ON)})	V _{CC} = 3.3 V,	Switch ON, V _{IN} = V _{CC} or GND,	V _{I/O} = 5.5 V, 3.3 V, or 0		9	11	pF
#		V _{CC} = 2.3 V,	$V_{I} = 0,$	$I_O = 30 \text{ mA}$		4	8	
		TYP at $V_{CC} = 2.5 \text{ V}$	V _I = 1.7 V,	$I_{O} = -15 \text{ mA}$		4.5	9	Ω
r _{on} #		Vac - 2 V	$V_{I} = 0,$	I _O = 30 mA		4	6	22
		VCC = 3 V	V _I = 2.4 V,	I _O = -15 mA		4	8	

VIN and IIN refer to control inputs. VI, VO, II, and IO refer to data pins.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figure 3)

PARAMETER	FROM	TO	V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
	(INPUT)	(OUTPUT)	MIN	MAX	MIN	MAX	
fOE	ŌĒ	A or B		10		20	MHz
t _{pd} ☆	A or B	B or A		0.12		0.20	ns
t _{en}	ŌE	A or B	1.5	7.5	1.5	6.5	ns
^t dis	ŌĒ	A or B	1	6.5	1	6.5	ns

 $[\]parallel$ Maximum switching frequency for control input (V_O > V_{CC}, V_I = 5 V, R_L ≥ 1 MΩ, C_L = 0)



[†] All typical values are at V_{CC} = 3.3 V (unless otherwise noted), T_A = 25°C.

[‡] For I/O ports, the parameter I_{OZ} includes the input leakage current.

[§] This is the increase in supply current for each input that is at the specified TTL voltage level, rather than V_{CC} or GND.

[¶] This parameter specifies the dynamic power-supply current associated with the operating frequency of a single control input (see Figure 2).

[#] Measured by the voltage drop between the A and B terminals at the indicated current through the switch. ON-state resistance is determined by the lower of the voltages of the two (A or B) terminals.

^{*}The propagation delay is the calculated RC time constant of the typical ON-state resistance of the switch and the specified load capacitance when driven by an ideal voltage source (zero output impedance).

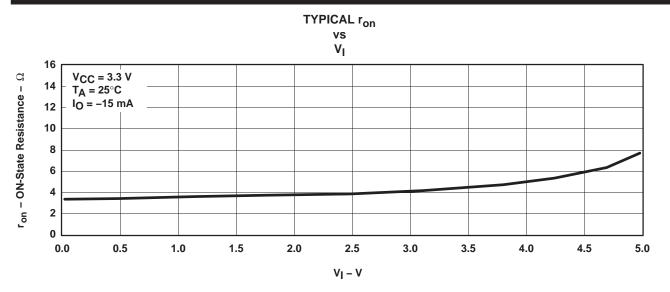


Figure 1. Typical r_{on} vs V_{I} , V_{CC} = 3.3 V and I_{O} = -15 mA

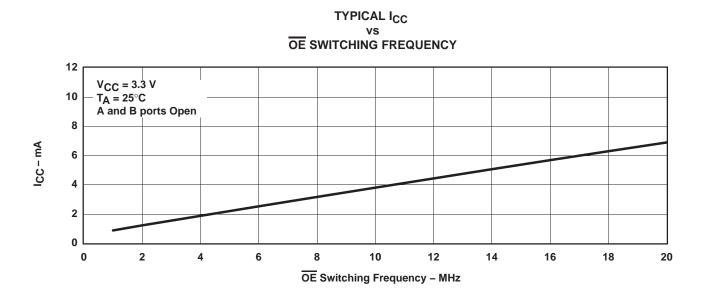
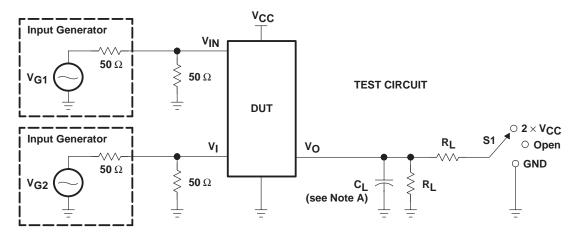


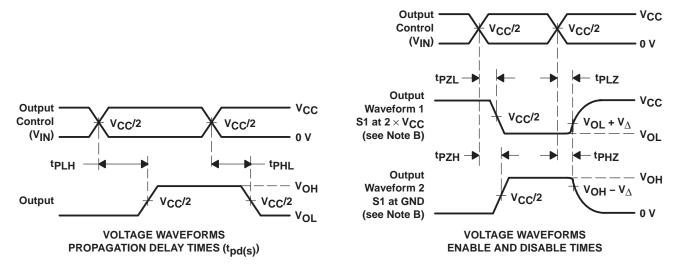
Figure 2. Typical I_{CC} vs \overline{OE} Switching Frequency, V_{CC} = 3.3 V



PARAMETER MEASUREMENT INFORMATION



TEST	VCC	S1	RL	VI	CL	${f v}_{\Delta}$
tpd(s)	2.5 V \pm 0.2 V	Open	500 Ω	V _{CC} or GND	30 pF	
pu(3)	3.3 V \pm 0.3 V	Open	500 Ω	V _{CC} or GND	50 pF	
tpl z/tpzl	2.5 V \pm 0.2 V	2×V _{CC}	500 Ω	GND	30 pF	0.15 V
'PLZ''PZL	3.3 V \pm 0.3 V	2×VCC	500 Ω	GND	50 pF	0.3 V
4/4	2.5 V ± 0.2 V	GND	500 Ω	VCC	30 pF	0.15 V
tPHZ/tPZH	3.3 V \pm 0.3 V	GND	500 Ω	VCC	50 pF	0.3 V



NOTES: A. C_L includes probe and jig capacitance.

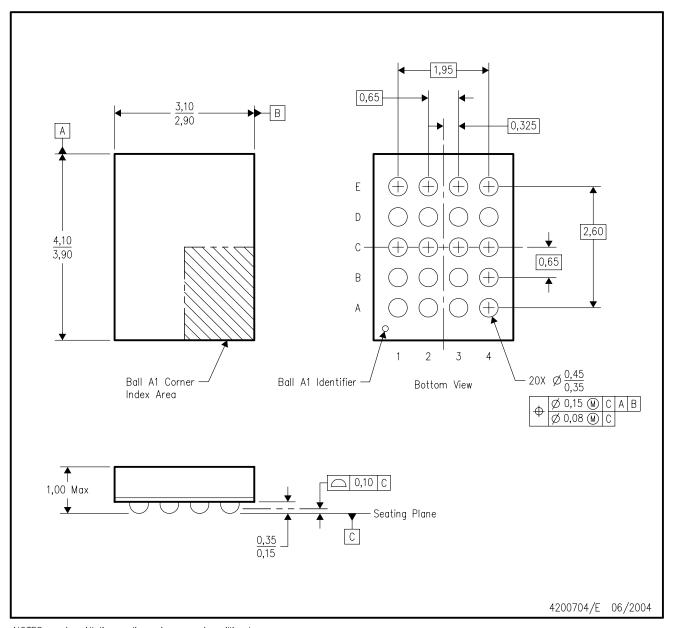
- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_Q = 50 \Omega$, $t_f \leq 2.5 \text{ ns.}$
- D. The outputs are measured one at a time with one transition per measurement.
- E. tpLZ and tpHZ are the same as tdis.
- F. tpzL and tpzH are the same as ten.
- G. tpLH and tpHL are the same as tpd(s). The tpd propagation delay is the calculated RC time constant of the typical ON-state resistance of the switch and the specified load capacitance, when driven by an ideal voltage source (zero output impedance).
- H. All parameters and waveforms are not applicable to all devices.

Figure 3. Test Circuit and Voltage Waveforms



GQN (R-PBGA-N20)

PLASTIC BALL GRID ARRAY



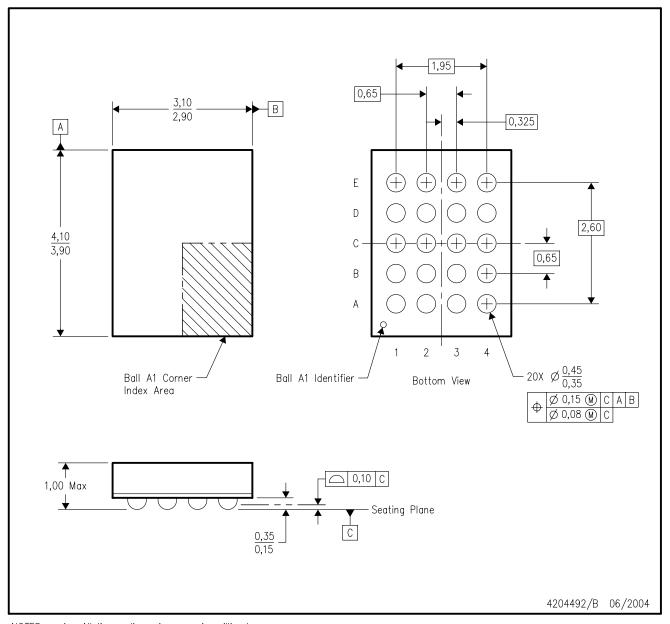
NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Falls within JEDEC MO-225 variation BC.
- D. This package is tin-lead (SnPb). Refer to the 20 ZQN package (drawing 4204492) for lead-free.



ZQN (R-PBGA-N20)

PLASTIC BALL GRID ARRAY



NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Falls within JEDEC MO-225 variation BC.
- D. This package is lead-free. Refer to the 20 GQN package (drawing 4200704) for tin-lead (SnPb).



DGV (R-PDSO-G**)

24 PINS SHOWN

PLASTIC SMALL-OUTLINE



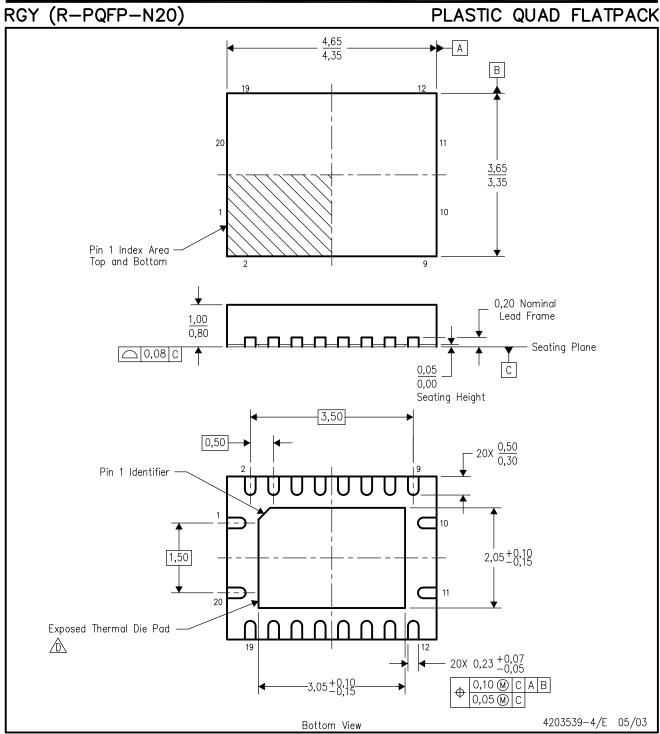
NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion, not to exceed 0,15 per side.

D. Falls within JEDEC: 24/48 Pins – MO-153 14/16/20/56 Pins – MO-194





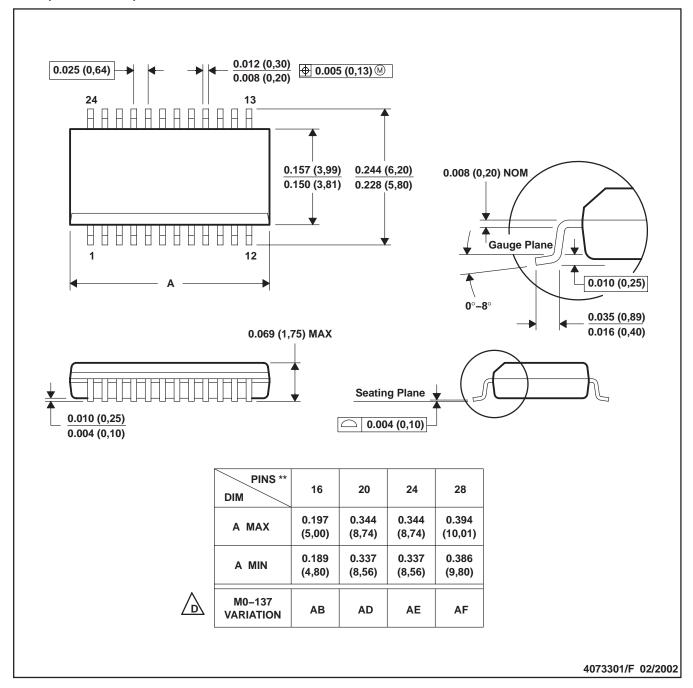
NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. QFN (Quad Flatpack No-Lead) package configuration.
- The package thermal performance may be enhanced by bonding the thermal die pad to an external thermal plane. This pad is electrically and thermally connected to the backside of the die and possibly selected ground leads.
- E. Package complies to JEDEC MO-241 variation BC.



DBQ (R-PDSO-G**)

PLASTIC SMALL-OUTLINE PACKAGE



NOTES: A. All linear dimensions are in inches (millimeters).

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).

D. Falls within JEDEC MO-137.



PW (R-PDSO-G**)

14 PINS SHOWN

PLASTIC SMALL-OUTLINE PACKAGE



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion not to exceed 0,15.

D. Falls within JEDEC MO-153

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